WHAT IS CLAIMED IS:

1. A surface acoustic wave device, comprising:

a quartz plate cut out with a Euler angle at (0°, 113° to 135°, +/-(40 to 49)°); and

a plurality of surface acoustic wave elements M1 to Mn connected together in parallel on a main surface of the quartz plate, and provided with at least a pair of IDT electrodes to generate a Rayleigh wave, surface acoustic waves having at least a plurality of different propagation directions of propagation directions $\psi 1$ to ψn being generated from the surface acoustic wave elements M1 to Mn, and the propagation directions $\psi 1$ to ψn satisfying a formula: $\psi 1$ to $\psi n = 0.3295\theta + 3.3318° +/- 1.125°$, with the Euler angle at (0°, θ, ψ).

2. A surface acoustic wave device, comprising:

a quartz plate cut out with a Euler angle at (0°, 113° to 135°, +/-(40 to 49)°); and

a plurality of surface acoustic wave elements M1 to Mn connected together in parallel on a main surface of the quartz plate, and provided with at least a pair of IDT electrodes to generate a Rayleigh wave, at least a plurality of different ratios $\eta 1$ to ηn obtained by dividing electrode width by electrode pitch of the IDT electrodes being given to the surface acoustic wave elements M1 to Mn, and the Euler angle at (0°, θ, ψ) satisfying a formula: $\psi = 0.3295\theta + 3.3318° +/- 1.125°$.

3. A surface acoustic wave device, comprising:

a quartz plate cut out with a Euler angle at (0°, 113° to 135°, +/-(40 to 49)°); and

a plurality of surface acoustic wave elements M1 to Mn connected together in parallel on a main surface of the quartz plate, and provided with at least a pair of IDT electrodes to generate a Rayleigh wave, at least a plurality of different ratios $\eta 1$ to ηn obtained by dividing electrode width by electrode pitch of the IDT electrodes being given to the surface acoustic wave elements M1 to Mn, surface acoustic waves having at least a plurality of different propagation directions of propagation directions $\psi 1$ to ψn being generated from the surface acoustic wave elements M1 to Mn, and the propagation directions $\psi 1$ to ψn satisfying a formula: $\psi 1$ to $\psi n = 0.3295\theta + 3.3318° +/- 1.125°$, with the Euler angle at (0°, θ, ψ).

4. The surface acoustic wave device according to claim 1, comprising:

at least one of turnover temperatures Tp1 to Tpn of a temperature characteristic obtained by each of the surface acoustic wave elements M1 to Mn being out of an operating temperature range.

5. The surface acoustic wave device according to claim 2, comprising:

at least one of turnover temperatures Tp1 to Tpn of a temperature characteristic obtained by each of the surface acoustic wave elements M1 to Mn being out of an operating temperature range.

6. The surface acoustic wave device according to claim 3, comprising:

at least one of turnover temperatures Tp1 to Tpn of a temperature characteristic obtained by each of the surface acoustic wave elements M1 to Mn being out of an operating temperature range.

7. A method of adjusting a temperature characteristic of the surface acoustic wave device according to claim 1, comprising:

adjusting the temperature characteristic by adjusting an angle of disposition of the surface acoustic wave device on the quartz plate cut out with a Euler angle at (0°, 113° to 135°, +/-(40 to 49)°).

8. A method of adjusting a temperature characteristic of the surface acoustic wave device according to claim 2, comprising:

adjusting the temperature characteristic by adjusting an angle of disposition of the surface acoustic wave device on the quartz plate cut out with a Euler angle at (0°, 113° to 135°, +/-(40 to 49)°).

9. A method of adjusting a temperature characteristic of the surface acoustic wave device according to claim 3, comprising:

adjusting the temperature characteristic by adjusting an angle of disposition of the surface acoustic wave device on the quartz plate cut out with a Euler angle at (0°, 113° to 135°, +/-(40 to 49)°).

10. A method of adjusting a temperature characteristic of the surface acoustic wave device according to claim 4, comprising:

adjusting the temperature characteristic by adjusting an angle of disposition of the surface acoustic wave device on the quartz plate cut out with a Euler angle at (0°, 113° to 135°, +/-(40 to 49)°).

11. A method of adjusting a temperature characteristic of the surface acoustic wave device according to claim 5, comprising:

adjusting the temperature characteristic by adjusting an angle of disposition of the surface acoustic wave device on the quartz plate cut out with a Euler angle at (0°, 113° to 135°, +/-(40 to 49)°).

12. A method of adjusting a temperature characteristic of the surface acoustic wave device according to claim 6, comprising:

adjusting the temperature characteristic by adjusting an angle of disposition of the surface acoustic wave device on the quartz plate cut out with a Euler angle at (0°, 113° to 135°, +/-(40 to 49)°).